

Substitute for form 1449A/PTO

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

*(use as many sheets as necessary)*

Sheet	1	of	2
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**Complete if Known**

Application Number	09/610,889
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Filing Date	July 6, 2000
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First Named Inventor	FINAROV et al.
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Group Art Unit	2877
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**Examiner Name**

Attorney Docket Number	FINAROV=3
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## U.S. PATENT DOCUMENTS

[illegible]

**FOREIGN PATENT DOCUMENTS**

[illegible]

Examiner  
Signature

Date  
Considered

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

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Sheet	2	of	2	Application Number	09/610,889
				Filing Date	July 6, 2000
				First Named Inventor	FINAROV et al.
				Group Art Unit	2877
				Examiner Name	
				Attorney Docket Number	FINAROV=3

**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
	AJ	VOSKOVTSOVA et al., <u>Soviet Journal of Optical Technology</u> , (1993) vol.60, no.9, pp.617-619	
	AK	ROGER et al, "Inverse scattering method in electromagnetic optics: Applications to diffraction grating", <u>J. Opt. Soc. Am.</u> , (1980), vol.70, No. 12, pp.1483-1495, Optical Society of America	
	AL	ROGER et al., "The perfectly conducting grating from the point of view of inverse diffraction", <u>Optica Acta</u> , (1979), vol.26, No. 4, pp.447-460, Taylor & Francis Ltd.	
	AM	ROGER et al., "Grating Profile Reconstruction by an Inverse Scattering Method" <u>Optics Communication</u> , (1980), vol.35, No.3, pp.299-302	
	AN	LOCHBIHLER et al., "Reconstruction of the profile of gold wire gratings: A comparison of different methods", <u>Optik</u> , (1994), vol.98, No.1, pp.21-25, Germany	
	AO	SAVITSKII et al., "Efficiency optimization of reflecting diffraction gratings with a trapezoidal groove profile", <u>Opt. Spectrosc.</u> , (1985), vol.59, No.2, pp.251-254, The Optical Society of America	
	AP	SPIKHAL'SKII, "Radiative Bragg Mirrors: Spectral Characteristics Versus Grating Groove Profile", <u>Optics Communication</u> , (1986), vol.57, No. 6, pp.375-379, Holland	
	AQ	NAQVI et al., "Etch depth estimation of large-period silicon grating with multivariate calibration of rigorously simulated diffraction profile", <u>Journal of the Optical Society of America</u> , (1994), vol.11, No.9, pp.2485-2493, Optical Society of America	
	AR	MOHARAM et al., "Rigorous coupled-wave analysis of planar-grating diffraction", <u>Journal of the Optical Society of America</u> , (1981), vol.71, No. 7, pp.811-818, Optical Society of America	
	AS	RAYMOND et al., "Resist and etched line profile characterization using scatterometry", <u>SPIE</u> , (1997), vol.3050, pp.476-486	

Examiner Signature		Date Considered	
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Sheet	1	of	1
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<b>Application Number</b>	09/610,889
<b>Filing Date</b>	July 6, 2000
<b>First Named Inventor</b>	Moshe FINAROV
<b>Group Art Unit</b>	2877
<b>Examiner Name</b>	
<b>Attorney Docket Number</b>	FINAROV=3

[illegible][illegible]

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